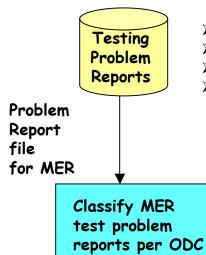
Adapting ODC for Empirical **Evaluation of Pre-Launch Anomalies** Dr. Robyn Lutz, JPL



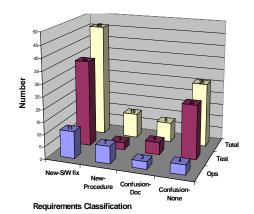
> Where are the spikes?

- >Phase-by-phase deltas?
- >Activity/Trigger/Target/
- > Type look nominal?

MER use:

> Focus on problem reports that involve requirements

- >Improvement release-by-release uneven: why?
- > Many closed with no fix: why?



Browse pivot chart (Excel) for overview/closer look at testing Categories

Discover defect patterns in testing of interest to MER

MER use: **Identify** patterns of concern for more investigation

Perform Root Cause Analysis on subset

Use on MER of ODC* defect analysis

Recommendations for MER and future projects:

- > Earlier assignment of criticality ratings
- >If software's behavior confused testers. enhance documentation
- > Earlier testing of fault-protection

MER use: **Improved** understanding of data, underlying causes, defect mechanisms

*ODC = Orthogonal Defect Classification technique [IBM]



R. Lutz and C. Mikulski. JPL 3/12/03

MER use: Implement/defer recommendations

· Develop and package recommendations for MER